

Search Notes

Application/Control No.

09/603,615

Examiner

Hanh Nguyen

Applicant(s)/Patent under
Reexamination

LEE, HEE-JIN

Art Unit

2662

SEARCHED

Class	Subclass	Date	Examiner
370	395.52	6/14/2005	HN
	400		
	351		
	469		
	352		
	470		
	465		
	466		
	467		
	471		
	431		
	410		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
370	395.52	6/14/2005	HN
	451		
	469		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East search	6/14/2005	HN